

Notice of References Cited		Application/Control No. 10/788,542	Applicant(s)/Patent Under Reexamination SCHEER ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0203283	08-2007	Scheer, Frederic	524/442
*	B	US-2007/0243374	10-2007	Lewis et al.	428/349
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2001-136658	01-2001	JP	Yoshida et al	
	O	2003-171544	06-2003	JP	Takagi et al	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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